

# Conference Committees

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# Preface

2016 International Conference on Measurement Instrumentation and Electronics provides a forum for accessing to the most up-to-date and authoritative knowledge from both industrial and academic worlds, sharing best practice in the field of measurement instrumentation and electronic.

The objective of the conference is to address and deliberate on the latest technical status and recent trends in the research and applications of measurement instrumentation and electronics. This conference has been designed with the view to provide an opportunity for researchers and engineers from both industrial and academic to interact and exchange their new ideas and research outcomes for future collaboration.

The first ICMIE was held in Munich, Germany during June 6-8, 2016. ICMIE 2016 was held with presentations delivered by researchers and scholars from the international community, including keynote speeches and highly selective lectures.

The present volume contains selected papers which were submitted to this conference and provides most comprehensive and worldwide state-of-the art knowledge in the field of measurement instrumentation and electronics. All papers included in this collection had undergone the careful peer-review by the conference technical committee members and international reviewers before they're selected for publication. Studies presented in this volume cover the following 10 research areas: electronic instruments and measurement technology, material properties analysis and measurement, signal processing and pattern recognition, mechanical automation, theory of measurement error, network technology, artificial intelligence, computer application technology, system modeling and analysis, the technology of electronic circuit.

We would like to take this opportunity to thank many people. First and foremost we want to express my deep appreciation to keynote speakers, session chairs, as well as all the reviewers for their efforts and kind help in this congress. Final thanks go to all authors and participants at ICMIE 2016 for contributing to the conference and make it a successful event.

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June 2016.